Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/810,596	FUJITA, KEN	
Examiner	Art Unit	
David Mic	2017	

	SEAR	CHED	
Class	Subclass	Date	Examiner
331	1A, 10, 18, 25, 36C, 66, 69-70	8/1/2005	.DM
	115, 117R		
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
USPGPUB	(see	8/1/2005	DM
	history)		

SEARCH NOT (INCLUDING SEARCH	TES STRATEGY	')
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